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Title

The device and method for measuring the parameters of nanosensors based on semiconductor nanostructured oxides in the range of microwatts

Authors

VERJBIŢKI Valeri, LUPAN Oleg, RAILEAN Serghei

Institution

Technical University of Moldova

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Description

EN

The device for measuring the resistance of nanostructure of semiconductor oxide sensors includes an adjustable reference voltage source connected to a series-connected nanostructure R_x and a reference resistance R_0 , the voltage drop of which is applied to the inputs of the microprocessor's analog-to-digital converters (ADC). Microprocessor controls the voltage of the regulated reference voltage source such that the electrical power dissipated on the nanostructure is not more of the given permissible value. The calculated resistance value of the nanostructure is displayed on a four-digit seven-segment display.

Class no.

1.